

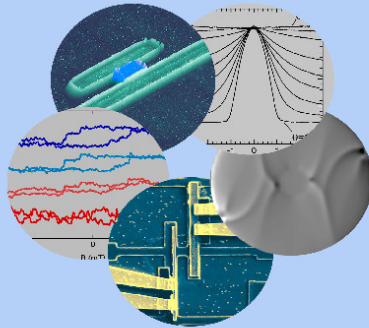


Marcus Steiner (Autor)

Micromagnetism and Electrical Resistance of Ferromagnetic Electrodes for Spin-Injection Devices

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of Ferromagnetic Electrodes for
Spin-Injection Devices



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